

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/628,259	HWU ET AL.	
Examiner	Art Unit	
LIOHN PAK	1616	

	SEAR	CHED	
Class	Subclass	Date	Examiner
UPVated	1:	1	
424	1 <u>;</u> 602-606 617,630	1/06	
	632 637-639		
	641-642 646-650		
	652,654 655,665 669-671		A
	669-671 675-682		} <i>(}}</i>
	685 692-698		
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	492-494		
	505,553 557-560		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor names searched	1/06	M		